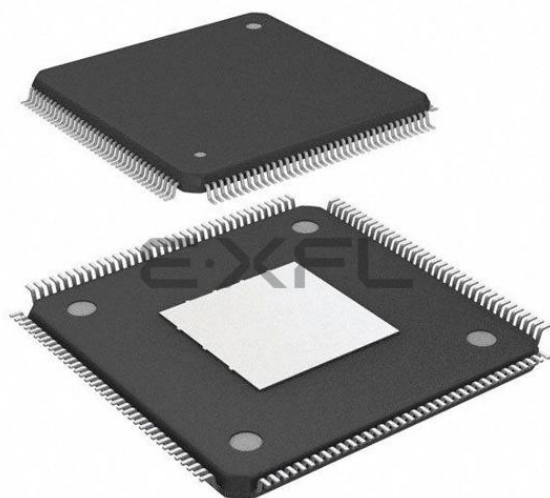




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Embedded - FPGAs, or Field Programmable Gate Arrays, are advanced integrated circuits that offer unparalleled flexibility and performance for digital systems. Unlike traditional fixed-function logic devices, FPGAs can be programmed and reprogrammed to execute a wide array of logical operations, enabling customized functionality tailored to specific applications. This reprogrammability allows developers to iterate designs quickly and implement complex functions without the need for custom hardware.

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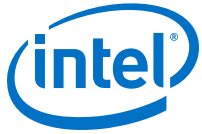
Details

Product Status	Active
Number of LABs/CLBs	125
Number of Logic Elements/Cells	2000
Total RAM Bits	110592
Number of I/O	101
Number of Gates	-
Voltage - Supply	2.85V ~ 3.465V
Mounting Type	Surface Mount
Operating Temperature	-40°C ~ 100°C (TJ)
Package / Case	144-LQFP Exposed Pad
Supplier Device Package	144-EQFP (20x20)
Purchase URL	https://www.e-xfl.com/product-detail/intel/10m02sce144i7g



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Operating Conditions

Intel MAX 10 devices are rated according to a set of defined parameters. To maintain the highest possible performance and reliability of the Intel MAX 10 devices, you must consider the operating requirements described in this section.

Absolute Maximum Ratings

This section defines the maximum operating conditions for Intel MAX 10 devices. The values are based on experiments conducted with the devices and theoretical modeling of breakdown and damage mechanisms. The functional operation of the device is not implied for these conditions.

Caution: Conditions outside the range listed in the absolute maximum ratings tables may cause permanent damage to the device. Additionally, device operation at the absolute maximum ratings for extended periods of time may have adverse effects on the device.

Single Supply Devices Absolute Maximum Ratings

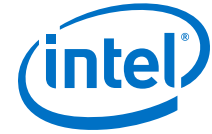
Table 2. Absolute Maximum Ratings for Intel MAX 10 Single Supply Devices

Symbol	Parameter	Min	Max	Unit
V _{CC_ONE}	Supply voltage for core and periphery through on-die voltage regulator	-0.5	3.9	V
V _{CCIO}	Supply voltage for input and output buffers	-0.5	3.9	V
V _{CCA}	Supply voltage for phase-locked loop (PLL) regulator and analog-to-digital converter (ADC) block (analog)	-0.5	3.9	V

Dual Supply Devices Absolute Maximum Ratings

Table 3. Absolute Maximum Ratings for Intel MAX 10 Dual Supply Devices

Symbol	Parameter	Min	Max	Unit
V _{CC}	Supply voltage for core and periphery	-0.5	1.63	V
V _{CCIO}	Supply voltage for input and output buffers	-0.5	3.9	V
V _{CCA}	Supply voltage for PLL regulator (analog)	-0.5	3.41	V
continued...				



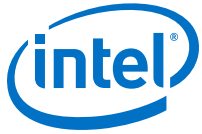
Symbol	Parameter	Condition	Min	Typ	Max	Unit
$V_{CCA}^{(1)}$	Supply voltage for PLL regulator and ADC block (analog)	1.35 V	1.2825	1.35	1.4175	V
		1.2 V	1.14	1.2	1.26	V
		—	2.85/3.135	3.0/3.3	3.15/3.465	V

Dual Supply Devices Power Supplies Recommended Operating Conditions

Table 7. Power Supplies Recommended Operating Conditions for Intel MAX 10 Dual Supply Devices

Symbol	Parameter	Condition	Min	Typ	Max	Unit
V_{CC}	Supply voltage for core and periphery	—	1.15	1.2	1.25	V
$V_{CCIO}^{(3)}$	Supply voltage for input and output buffers	3.3 V	3.135	3.3	3.465	V
		3.0 V	2.85	3	3.15	V
		2.5 V	2.375	2.5	2.625	V
		1.8 V	1.71	1.8	1.89	V
		1.5 V	1.425	1.5	1.575	V
		1.35 V	1.2825	1.35	1.4175	V
		1.2 V	1.14	1.2	1.26	V
$V_{CCA}^{(4)}$	Supply voltage for PLL regulator (analog)	—	2.375	2.5	2.625	V
$V_{CCD_PLL}^{(5)}$	Supply voltage for PLL regulator (digital)	—	1.15	1.2	1.25	V
V_{CCA_ADC}	Supply voltage for ADC analog block	—	2.375	2.5	2.625	V
V_{CCINT}	Supply voltage for ADC digital block	—	1.15	1.2	1.25	V

- (3) V_{CCIO} for all I/O banks must be powered up during user mode because V_{CCIO} I/O banks are used for the ADC and I/O functionalities.
- (4) All V_{CCA} pins must be powered to 2.5 V (even when PLLs are not used), and must be powered up and powered down at the same time.
- (5) V_{CCD_PLL} must always be connected to V_{CC} through a decoupling capacitor and ferrite bead.



Pin Capacitance

Table 16. Pin Capacitance for Intel MAX 10 Devices

Symbol	Parameter	Maximum	Unit
C _{IOB}	Input capacitance on bottom I/O pins	8	pF
C _{IOLRT}	Input capacitance on left/right/top I/O pins	7	pF
C _{LVDSB}	Input capacitance on bottom I/O pins with dedicated LVDS output ⁽⁹⁾	8	pF
C _{ADCL}	Input capacitance on left I/O pins with ADC input ⁽¹⁰⁾	9	pF
C _{VREFLRT}	Input capacitance on left/right/top dual purpose V _{REF} pin when used as V _{REF} or user I/O pin ⁽¹¹⁾	48	pF
C _{VREFB}	Input capacitance on bottom dual purpose V _{REF} pin when used as V _{REF} or user I/O pin	50	pF
C _{CLKB}	Input capacitance on bottom dual purpose clock input pins ⁽¹²⁾	7	pF
C _{CLKLRT}	Input capacitance on left/right/top dual purpose clock input pins ⁽¹²⁾	6	pF

Internal Weak Pull-Up Resistor

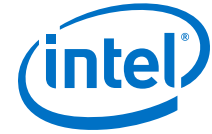
All I/O pins, except configuration, test, and JTAG pins, have an option to enable weak pull-up.

⁽⁹⁾ Dedicated LVDS output buffer is only available at bottom I/O banks.

⁽¹⁰⁾ ADC pins are only available at left I/O banks.

⁽¹¹⁾ When V_{REF} pin is used as regular input or output, F_{max} performance is reduced due to higher pin capacitance. Using the V_{REF} pin capacitance specification from device datasheet, perform SI analysis on your board setup to determine the F_{max} of your system.

⁽¹²⁾ 10M40 and 10M50 devices have dual purpose clock input pins at top/bottom I/O banks.

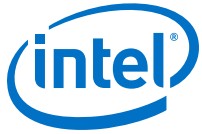


Single-Ended I/O Standards Specifications

Table 20. Single-Ended I/O Standards Specifications for Intel MAX 10 Devices

To meet the I_{OL} and I_{OH} specifications, you must set the current strength settings accordingly. For example, to meet the 3.3-V LVTTTL specification (4 mA), you should set the current strength settings to 4 mA. Setting at lower current strength may not meet the I_{OL} and I_{OH} specifications in the datasheet.

I/O Standard	V_{CCIO} (V)			V_{IL} (V)		V_{IH} (V)		V_{OL} (V)	V_{OH} (V)	I_{OL} (mA)	I_{OH} (mA)
	Min	Typ	Max	Min	Max	Min	Max	Max	Min		
3.3 V LVTTTL	3.135	3.3	3.465	-0.3	0.8	1.7	3.6	0.45	2.4	4	-4
3.3 V LVCMOS	3.135	3.3	3.465	-0.3	0.8	1.7	3.6	0.2	$V_{CCIO} - 0.2$	2	-2
3.0 V LVTTTL	2.85	3	3.15	-0.3	0.8	1.7	$V_{CCIO} + 0.3$	0.45	2.4	4	-4
3.0 V LVCMOS	2.85	3	3.15	-0.3	0.8	1.7	$V_{CCIO} + 0.3$	0.2	$V_{CCIO} - 0.2$	0.1	-0.1
2.5 V LVTTTL and LVCMOS	2.375	2.5	2.625	-0.3	0.7	1.7	$V_{CCIO} + 0.3$	0.4	2	1	-1
1.8 V LVTTTL and LVCMOS	1.71	1.8	1.89	-0.3	$0.35 \times V_{CCIO}$	$0.65 \times V_{CCIO}$	2.25	0.45	$V_{CCIO} - 0.45$	2	-2
1.5 V LVCMOS	1.425	1.5	1.575	-0.3	$0.35 \times V_{CCIO}$	$0.65 \times V_{CCIO}$	$V_{CCIO} + 0.3$	$0.25 \times V_{CCIO}$	$0.75 \times V_{CCIO}$	2	-2
1.2 V LVCMOS	1.14	1.2	1.26	-0.3	$0.35 \times V_{CCIO}$	$0.65 \times V_{CCIO}$	$V_{CCIO} + 0.3$	$0.25 \times V_{CCIO}$	$0.75 \times V_{CCIO}$	2	-2
3.3 V Schmitt Trigger	3.135	3.3	3.465	-0.3	0.8	1.7	$V_{CCIO} + 0.3$	—	—	—	—
2.5 V Schmitt Trigger	2.375	2.5	2.625	-0.3	0.7	1.7	$V_{CCIO} + 0.3$	—	—	—	—
1.8 V Schmitt Trigger	1.71	1.8	1.89	-0.3	$0.35 \times V_{CCIO}$	$0.65 \times V_{CCIO}$	$V_{CCIO} + 0.3$	—	—	—	—
1.5 V Schmitt Trigger	1.425	1.5	1.575	-0.3	$0.35 \times V_{CCIO}$	$0.65 \times V_{CCIO}$	$V_{CCIO} + 0.3$	—	—	—	—
3.0 V PCI	2.85	3	3.15	—	$0.3 \times V_{CCIO}$	$0.5 \times V_{CCIO}$	$V_{CCIO} + 0.3$	$0.1 \times V_{CCIO}$	$0.9 \times V_{CCIO}$	1.5	-0.5



Single-Ended SSTL, HSTL, and HSUL I/O Reference Voltage Specifications

Table 21. Single-Ended SSTL, HSTL, and HSUL I/O Reference Voltage Specifications for Intel MAX 10 Devices

I/O Standard	V _{CCIO} (V)			V _{REF} (V)			V _{TT} (V) ⁽¹⁴⁾		
	Min	Typ	Max	Min	Typ	Max	Min	Typ	Max
SSTL-2 Class I, II	2.375	2.5	2.625	1.19	1.25	1.31	V _{REF} - 0.04	V _{REF}	V _{REF} + 0.04
SSTL-18 Class I, II	1.7	1.8	1.9	0.833	0.9	0.969	V _{REF} - 0.04	V _{REF}	V _{REF} + 0.04
SSTL-15 Class I, II	1.425	1.5	1.575	0.49 × V _{CCIO}	0.5 × V _{CCIO}	0.51 × V _{CCIO}	0.49 × V _{CCIO}	0.5 × V _{CCIO}	0.51 × V _{CCIO}
SSTL-135 Class I, II	1.283	1.35	1.45	0.49 × V _{CCIO}	0.5 × V _{CCIO}	0.51 × V _{CCIO}	0.49 × V _{CCIO}	0.5 × V _{CCIO}	0.51 × V _{CCIO}
HSTL-18 Class I, II	1.71	1.8	1.89	0.85	0.9	0.95	0.85	0.9	0.95
HSTL-15 Class I, II	1.425	1.5	1.575	0.71	0.75	0.79	0.71	0.75	0.79
HSTL-12 Class I, II	1.14	1.2	1.26	0.48 × V _{CCIO} ⁽¹⁵⁾	0.5 × V _{CCIO} ⁽¹⁵⁾	0.52 × V _{CCIO} ⁽¹⁵⁾	—	0.5 × V _{CCIO}	—
				0.47 × V _{CCIO} ⁽¹⁶⁾	0.5 × V _{CCIO} ⁽¹⁶⁾	0.53 × V _{CCIO} ⁽¹⁶⁾			
HSUL-12	1.14	1.2	1.3	0.49 × V _{CCIO}	0.5 × V _{CCIO}	0.51 × V _{CCIO}	—	—	—

⁽¹⁴⁾ V_{TT} of transmitting device must track V_{REF} of the receiving device.

⁽¹⁵⁾ Value shown refers to DC input reference voltage, V_{REF(DC)}.

⁽¹⁶⁾ Value shown refers to AC input reference voltage, V_{REF(AC)}.



Symbol	Parameter	Condition	Min	Typ	Max	Unit
t_{PLL_PSERR}	Accuracy of PLL phase shift	—	—	—	±50	ps
t_{ARESET}	Minimum pulse width on areset signal.	—	10	—	—	ns
$t_{CONFIGPLL}$	Time required to reconfigure scan chains for PLLs	—	—	3.5 ⁽³²⁾	—	SCANCLK cycles
$f_{SCANCLK}$	scanclk frequency	—	—	—	100	MHz

Table 28. PLL Specifications for Intel MAX 10 Single Supply Devices

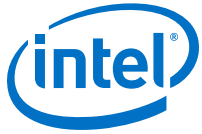
For V36 package, the PLL specification is based on single supply devices.

Symbol	Parameter	Condition	Max	Unit
$t_{OUTJITTER_PERIOD_DEDCLK}$ ⁽³¹⁾	Dedicated clock output period jitter	$F_{OUT} \geq 100$ MHz	660	ps
		$F_{OUT} < 100$ MHz	66	mUI
$t_{OUTJITTER_CCJ_DEDCLK}$ ⁽³¹⁾	Dedicated clock output cycle-to-cycle jitter	$F_{OUT} \geq 100$ MHz	660	ps
		$F_{OUT} < 100$ MHz	66	mUI

Table 29. PLL Specifications for Intel MAX 10 Dual Supply Devices

Symbol	Parameter	Condition	Max	Unit
$t_{OUTJITTER_PERIOD_DEDCLK}$ ⁽³¹⁾	Dedicated clock output period jitter	$F_{OUT} \geq 100$ MHz	300	ps
		$F_{OUT} < 100$ MHz	30	mUI
$t_{OUTJITTER_CCJ_DEDCLK}$ ⁽³¹⁾	Dedicated clock output cycle-to-cycle jitter	$F_{OUT} \geq 100$ MHz	300	ps
		$F_{OUT} < 100$ MHz	30	mUI

⁽³²⁾ With 100 MHz scanclk frequency.



Parameter		Symbol	Condition	Min	Typ	Max	Unit
	Integral non linearity	INL	—	–2	—	2	LSB
AC Accuracy	Total harmonic distortion	THD	$F_{IN} = 50 \text{ kHz}$, $F_S = 1 \text{ MHz}$, PLL	–65 ⁽³⁷⁾	—	—	dB
	Signal-to-noise ratio	SNR	$F_{IN} = 50 \text{ kHz}$, $F_S = 1 \text{ MHz}$, PLL	54 ⁽³⁸⁾	—	—	dB
	Signal-to-noise and distortion	SINAD	$F_{IN} = 50 \text{ kHz}$, $F_S = 1 \text{ MHz}$, PLL	53 ⁽³⁹⁾	—	—	dB
On-Chip Temperature Sensor	Temperature sampling rate	T_S	—	—	—	50	kSPS
	Absolute accuracy	—	–40 to 125°C, with 64 samples averaging ⁽⁴⁰⁾	—	—	±10	°C
Conversion Rate ⁽⁴¹⁾	Conversion time	—	Single measurement	—	—	1	Cycle
			Continuous measurement	—	—	1	Cycle
			Temperature measurement	—	—	1	Cycle

Related Information

[SPICE Models for Intel FPGAs](#)

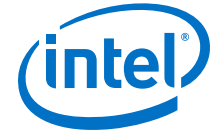
⁽³⁷⁾ THD with prescaler enabled is 6dB less than the specification.

⁽³⁸⁾ SNR with prescaler enabled is 6dB less than the specification.

⁽³⁹⁾ SINAD with prescaler enabled is 6dB less than the specification.

⁽⁴⁰⁾ For the Intel Quartus Prime software version 15.0 and later, Modular ADC Core Intel FPGA IP and Modular Dual ADC Core Intel FPGA IP cores handle the 64 samples averaging. For the Intel Quartus Prime software versions prior to 14.1, you need to implement your own averaging calculation.

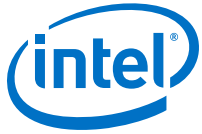
⁽⁴¹⁾ For more detailed description, refer to the Timing section in the *Intel MAX 10 Analog-to-Digital Converter User Guide*.



Symbol	Parameter	Mode	-I6, -A6, -C7, -I7			-A7			-C8			Unit
			Min	Typ	Max	Min	Typ	Max	Min	Typ	Max	
		×4	40	—	300	40	—	300	40	—	300	Mbps
		×2	20	—	300	20	—	300	20	—	300	Mbps
		×1	10	—	300	10	—	300	10	—	300	Mbps
t _{DUTY}	Duty cycle on transmitter output clock	—	45	—	55	45	—	55	45	—	55	%
TCCS ⁽⁵³⁾	Transmitter channel-to-channel skew	—	—	—	300	—	—	300	—	—	300	ps
t _{x jitter} ⁽⁵⁴⁾	Output jitter (high-speed I/O performance pin)	—	—	—	425	—	—	425	—	—	425	ps
	Output jitter (low-speed I/O performance pin)	—	—	—	470	—	—	470	—	—	470	ps
t _{RISE}	Rise time	20 – 80%, C _{LOAD} = 5 pF	—	500	—	—	500	—	—	500	—	ps
t _{FALL}	Fall time	20 – 80%, C _{LOAD} = 5 pF	—	500	—	—	500	—	—	500	—	ps
t _{LOCK}	Time required for the PLL to lock, after CONF_DONE signal goes high, indicating the completion of device configuration	—	—	—	1	—	—	1	—	—	1	ms

⁽⁵³⁾ TCCS specifications apply to I/O banks from the same side only.

⁽⁵⁴⁾ TX jitter is the jitter induced from core noise and I/O switching noise.



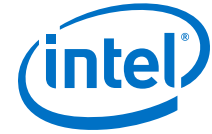
Dual Supply Devices True RSDS and Emulated RSDS_E_3R Transmitter Timing Specifications

Table 38. True RSDS and Emulated RSDS_E_3R Transmitter Timing Specifications for Intel MAX 10 Dual Supply Devices

True **RSDS** transmitter is only supported at bottom I/O banks. Emulated **RSDS** transmitter is supported at the output pin of all I/O banks.

Symbol	Parameter	Mode	-I6, -A6, -C7, -I7			-A7			-C8			Unit
			Min	Typ	Max	Min	Typ	Max	Min	Typ	Max	
f _{HCLK}	Input clock frequency (high-speed I/O performance pin)	×10	5	—	155	5	—	155	5	—	155	MHz
		×8	5	—	155	5	—	155	5	—	155	MHz
		×7	5	—	155	5	—	155	5	—	155	MHz
		×4	5	—	155	5	—	155	5	—	155	MHz
		×2	5	—	155	5	—	155	5	—	155	MHz
		×1	5	—	310	5	—	310	5	—	310	MHz
HSIODR	Data rate (high-speed I/O performance pin)	×10	100	—	310	100	—	310	100	—	310	Mbps
		×8	80	—	310	80	—	310	80	—	310	Mbps
		×7	70	—	310	70	—	310	70	—	310	Mbps
		×4	40	—	310	40	—	310	40	—	310	Mbps
		×2	20	—	310	20	—	310	20	—	310	Mbps
		×1	10	—	310	10	—	310	10	—	310	Mbps
f _{HCLK}	Input clock frequency (low-speed I/O performance pin)	×10	5	—	150	5	—	150	5	—	150	MHz
		×8	5	—	150	5	—	150	5	—	150	MHz
		×7	5	—	150	5	—	150	5	—	150	MHz
		×4	5	—	150	5	—	150	5	—	150	MHz
		×2	5	—	150	5	—	150	5	—	150	MHz
		×1	5	—	300	5	—	300	5	—	300	MHz
HSIODR	Data rate (low-speed I/O performance pin)	×10	100	—	300	100	—	300	100	—	300	Mbps
		×8	80	—	300	80	—	300	80	—	300	Mbps
		×7	70	—	300	70	—	300	70	—	300	Mbps

continued...



Symbol	Parameter	Mode	-I6, -A6, -C7, -I7			-A7			-C8			Unit
			Min	Typ	Max	Min	Typ	Max	Min	Typ	Max	
		×4	40	—	170	40	—	170	40	—	170	Mbps
		×2	20	—	170	20	—	170	20	—	170	Mbps
		×1	10	—	170	10	—	170	10	—	170	Mbps
t _{DUTY}	Duty cycle on transmitter output clock	—	45	—	55	45	—	55	45	—	55	%
TCCS ⁽⁵⁹⁾	Transmitter channel-to-channel skew	—	—	—	300	—	—	300	—	—	300	ps
t _{x jitter} ⁽⁶⁰⁾	Output jitter (high-speed I/O performance pin)	—	—	—	425	—	—	425	—	—	425	ps
	Output jitter (low-speed I/O performance pin)	—	—	—	470	—	—	470	—	—	470	ps
t _{RISE}	Rise time	20 – 80%, C _{LOAD} = 5 pF	—	500	—	—	500	—	—	500	—	ps
t _{FALL}	Fall time	20 – 80%, C _{LOAD} = 5 pF	—	500	—	—	500	—	—	500	—	ps
t _{LOCK}	Time required for the PLL to lock, after CONF_DONE signal goes high, indicating the completion of device configuration	—	—	—	1	—	—	1	—	—	1	ms

⁽⁵⁹⁾ TCCS specifications apply to I/O banks from the same side only.

⁽⁶⁰⁾ TX jitter is the jitter induced from core noise and I/O switching noise.



Symbol	Parameter	Mode	-I6, -A6, -C7, -I7			-A7			-C8			Unit
			Min	Typ	Max	Min	Typ	Max	Min	Typ	Max	
		×7	70	—	300	70	—	300	70	—	300	Mbps
		×4	40	—	300	40	—	300	40	—	300	Mbps
		×2	20	—	300	20	—	300	20	—	300	Mbps
		×1	10	—	300	10	—	300	10	—	300	Mbps
t _{DUTY}	Duty cycle on transmitter output clock	—	45	—	55	45	—	55	45	—	55	%
TCCS ⁽⁶¹⁾	Transmitter channel-to-channel skew	—	—	—	300	—	—	300	—	—	300	ps
t _{x jitter} ⁽⁶²⁾	Output jitter (high-speed I/O performance pin)	—	—	—	425	—	—	425	—	—	425	ps
	Output jitter (low-speed I/O performance pin)	—	—	—	470	—	—	470	—	—	470	ps
t _{RISE}	Rise time	20 – 80%, C _{LOAD} = 5 pF	—	500	—	—	500	—	—	500	—	ps
t _{FALL}	Fall time	20 – 80%, C _{LOAD} = 5 pF	—	500	—	—	500	—	—	500	—	ps
t _{LOCK}	Time required for the PLL to lock, after CONF_DONE signal goes high, indicating the completion of device configuration	—	—	—	1	—	—	1	—	—	1	ms

⁽⁶¹⁾ TCCS specifications apply to I/O banks from the same side only.

⁽⁶²⁾ TX jitter is the jitter induced from core noise and I/O switching noise.



Symbol	Parameter	Mode	-C7, -I7		-A7		-C8		Unit
			Min	Max	Min	Max	Min	Max	
		×8	80	200	80	200	80	200	Mbps
		×7	70	200	70	200	70	200	Mbps
		×4	40	200	40	200	40	200	Mbps
		×2	20	200	20	200	20	200	Mbps
		×1	10	200	10	200	10	200	Mbps
SW	Sampling window (high-speed I/O performance pin)	—	—	910	—	910	—	910	ps
	Sampling window (low-speed I/O performance pin)	—	—	1,110	—	1,110	—	1,110	ps
$t_{x \text{ jitter}}^{(71)}$	Input jitter	—	—	1,000	—	1,000	—	1,000	ps
t_{LOCK}	Time required for the PLL to lock, after CONF_DONE signal goes high, indicating the completion of device configuration	—	—	1	—	1	—	1	ms

Dual Supply Devices LVDS, TMDS, HiSpi, SLVS, and Sub-LVDS Receiver Timing Specifications

Table 46. LVDS, TMDS, HiSpi, SLVS, and Sub-LVDS Receiver Timing Specifications for Intel MAX 10 Dual Supply Devices

LVDS, TMDS, HiSpi, SLVS, and Sub-LVDS receivers are supported at all banks.

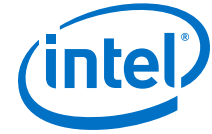
Symbol	Parameter	Mode	-I6, -A6, -C7, -I7		-A7		-C8		Unit
			Min	Max	Min	Max	Min	Max	
f_{HCLK}	Input clock frequency (high-speed I/O performance pin)	×10	5	350	5	320	5	320	MHz
		×8	5	360	5	320	5	320	MHz
		×7	5	350	5	320	5	320	MHz
		×4	5	360	5	320	5	320	MHz

continued...

⁽⁷¹⁾ TX jitter is the jitter induced from core noise and I/O switching noise.



Symbol	Parameter	Mode	-I6, -A6, -C7, -I7		-A7		-C8		Unit
			Min	Max	Min	Max	Min	Max	
		×2	5	360	5	320	5	320	MHz
		×1	5	360	5	320	5	320	MHz
HSIODR	Data rate (high-speed I/O performance pin)	×10	100	700	100	640	100	640	Mbps
		×8	80	720	80	640	80	640	Mbps
		×7	70	700	70	640	70	640	Mbps
		×4	40	720	40	640	40	640	Mbps
		×2	20	720	20	640	20	640	Mbps
		×1	10	360	10	320	10	320	Mbps
		×1	10	360	10	320	10	320	Mbps
f _{HSCLK}	Input clock frequency (low-speed I/O performance pin)	×10	5	150	5	150	5	150	MHz
		×8	5	150	5	150	5	150	MHz
		×7	5	150	5	150	5	150	MHz
		×4	5	150	5	150	5	150	MHz
		×2	5	150	5	150	5	150	MHz
		×1	5	300	5	300	5	300	MHz
		×1	5	300	5	300	5	300	MHz
HSIODR	Data rate (low-speed I/O performance pin)	×10	100	300	100	300	100	300	Mbps
		×8	80	300	80	300	80	300	Mbps
		×7	70	300	70	300	70	300	Mbps
		×4	40	300	40	300	40	300	Mbps
		×2	20	300	20	300	20	300	Mbps
		×1	10	300	10	300	10	300	Mbps
		×1	10	300	10	300	10	300	Mbps
SW	Sampling window (high-speed I/O performance pin)	—	—	510	—	510	—	510	ps
continued...									



Memory Output Clock Jitter Specifications

Intel MAX 10 devices support external memory interfaces up to 303 MHz. The external memory interfaces for Intel MAX 10 devices calibrate automatically.

The memory output clock jitter measurements are for 200 consecutive clock cycles.

The clock jitter specification applies to memory output clock pins generated using DDIO circuits clocked by a PLL output routed on a PHY clock network.

DDR3 and LPDDR2 SDRAM memory interfaces are only supported on the fast speed grade device.

Table 48. Memory Output Clock Jitter Specifications for Intel MAX 10 Devices

Parameter	Symbol	–6 Speed Grade		–7 Speed Grade		Unit
		Min	Max	Min	Max	
Clock period jitter	$t_{JIT(per)}$	–127	127	–215	215	ps
Cycle-to-cycle period jitter	$t_{JIT(cc)}$	—	242	—	360	ps

Related Information

[Literature: External Memory Interfaces](#)

Provides more information about external memory system performance specifications, board design guidelines, timing analysis, simulation, and debugging information.

Configuration Specifications

This section provides configuration specifications and timing for Intel MAX 10 devices.



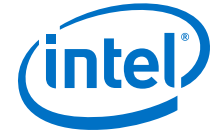
JTAG Timing Parameters

Table 49. JTAG Timing Parameters for Intel MAX 10 Devices

The values are based on $C_L = 10$ pF of TD0.

The affected Boundary Scan Test (BST) instructions are SAMPLE/PRELOAD, EXTEST, INTEST, and CHECK_STATUS.

Symbol	Parameter	Non-BST and non-CONFIG_IO Operation		BST and CONFIG_IO Operation		Unit
		Minimum	Maximum	Minimum	Maximum	
t_{JCP}	TCK clock period	40	—	50	—	ns
t_{JCH}	TCK clock high time	20	—	25	—	ns
t_{JCL}	TCK clock low time	20	—	25	—	ns
t_{JPSU_TDI}	JTAG port setup time	2	—	2	—	ns
t_{JPSU_TMS}	JTAG port setup time	3	—	3	—	ns
t_{JPH}	JTAG port hold time	10	—	10	—	ns
t_{JPCO}	JTAG port clock to output	—	15 (for $V_{CCIO} = 3.3, 3.0,$ and 2.5 V) 17 (for $V_{CCIO} = 1.8$ and 1.5 V)	—	18 (for $V_{CCIO} = 3.3, 3.0,$ and 2.5 V) 20 (for $V_{CCIO} = 1.8$ and 1.5 V)	ns
t_{JPZX}	JTAG port high impedance to valid output	—	15 (for $V_{CCIO} = 3.3, 3.0,$ and 2.5 V) 17 (for $V_{CCIO} = 1.8$ and 1.5 V)	—	15 (for $V_{CCIO} = 3.3, 3.0,$ and 2.5 V) 17 (for $V_{CCIO} = 1.8$ and 1.5 V)	ns
t_{JPXZ}	JTAG port valid output to high impedance	—	15 (for $V_{CCIO} = 3.3, 3.0,$ and 2.5 V) 17 (for $V_{CCIO} = 1.8$ and 1.5 V)	—	15 (for $V_{CCIO} = 3.3, 3.0,$ and 2.5 V) 17 (for $V_{CCIO} = 1.8$ and 1.5 V)	ns



Remote System Upgrade Circuitry Timing Specifications

Table 50. Remote System Upgrade Circuitry Timing Specifications for Intel MAX 10 Devices

Parameter	Device	Minimum	Maximum	Unit
t _{MAX_RU_CLK}	All	—	40	MHz
t _{RU_nCONFIG}	10M02, 10M04, 10M08, 10M16, 10M25	250	—	ns
	10M40, 10M50	350	—	ns
t _{RU_nRSTIMER}	10M02, 10M04, 10M08, 10M16, 10M25	300	—	ns
	10M40, 10M50	500	—	ns

User Watchdog Internal Circuitry Timing Specifications

Table 51. User Watchdog Timer Specifications for Intel MAX 10 Devices

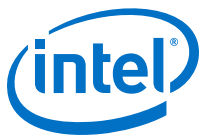
The specifications are subject to PVT changes.

Parameter	Device	Minimum	Typical	Maximum	Unit
User watchdog frequency	10M02, 10M04, 10M08, 10M16, 10M25	3.4	5.1	7.3	MHz
	10M40, 10M50	2.2	3.3	4.8	MHz

Uncompressed Raw Binary File (.rbf) Sizes

Table 52. Uncompressed .rbf Sizes for Intel MAX 10 Devices

Device	CFM Data Size (bits)	
	Without Memory Initialization	With Memory Initialization
10M02	554,000	—
10M04	1,540,000	1,880,000
10M08	1,540,000	1,880,000
10M16	2,800,000	3,430,000
<i>continued...</i>		



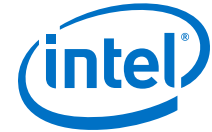
Glossary

Table 59. Glossary

Term	Definition
JTAG Timing Specifications	The diagram illustrates the JTAG timing specifications. It shows four signals: TMS, TDI, TCK, and TDO. TMS and TDI are shown as high-impedance signals. TCK is a clock signal with timing parameters t_{JCP}, t_{JCH}, t_{JCL}, t_{JPSU}, and t_{JPH}. TDO is a data signal with timing parameters t_{JPZX}, t_{JPCO}, and t_{JPXZ}.
R_L	Receiver differential input discrete resistor (external to Intel MAX 10 devices).
RSKM (Receiver input skew margin)	HIGH-SPEED I/O block: The total margin left after accounting for the sampling window and TCCS. $RSKM = (TUI - SW - TCCS) / 2$.
Sampling window (SW)	HIGH-SPEED I/O Block: The period of time during which the data must be valid to capture it correctly. The setup and hold times determine the ideal strobe position in the sampling window.
Single-ended voltage referenced I/O standard	The AC input signal values indicate the voltage levels at which the receiver must meet its timing specifications. The DC input signal values indicate the voltage levels at which the final logic state of the receiver is unambiguously defined. After the receiver input crosses the AC value, the receiver changes to the new logic state. The new logic state is then maintained as long as the input stays beyond the DC threshold. This approach is intended to provide predictable receiver timing in the presence of input waveform ringing.
t_c	High-speed receiver/transmitter input and output clock period.
TCCS (Channel-to- channel-skew)	HIGH-SPEED I/O block: The timing difference between the fastest and slowest output edges, including t_{CO} variation and clock skew. The clock is included in the TCCS measurement.
t_{cin}	Delay from clock pad to I/O input register.
t_{CO}	Delay from clock pad to I/O output.
t_{cout}	Delay from clock pad to I/O output register.
continued...	



Date	Version	Changes
January 2016	2016.01.22	• Added description about automotive temperature devices in the Programming/Erasure Specifications table. • Changed the pin capacitance to maximum values. • Updated maximum TCCS specifications from 410 ps to 300 ps in the following tables: — True PPDS and Emulated PPDS_E_3R Transmitter Timing Specifications for Intel MAX 10 Dual Supply Devices — True RSDS and Emulated RSDS_E_3R Transmitter Timing Specifications for Intel MAX 10 Dual Supply Devices — Emulated RSDS_E_1R Transmitter Timing Specifications for Intel MAX 10 Dual Supply Devices — True Mini-LVDS and Emulated Mini-LVDS_E_3R Transmitter Timing Specifications for Intel MAX 10 Dual Supply Devices — True LVDS Transmitter Timing Specifications for Intel MAX 10 Single Supply Devices — True LVDS Transmitter Timing Specifications for Intel MAX 10 Dual Supply Devices — Emulated LVDS_E_3R Transmitter Timing Specifications for Intel MAX 10 Single Supply Devices — Emulated LVDS_E_3R, SLVS, and Sub-LVDS Transmitter Timing Specifications for Intel MAX 10 Dual Supply Devices • Added new table: True RSDS and Emulated RSDS_E_3R Transmitter Timing Specifications for Intel MAX 10 Single Supply Devices. • Updated maximum f_{HCLK} and HSIO DR specifications for -A6, -C7, and -I7 speed grades in True LVDS Transmitter Timing Specifications for Intel MAX 10 Dual Supply Devices table. • Updated SW specifications in the following tables: — LVDS Receiver Timing Specifications for Intel MAX 10 Single Supply Devices — LVDS, TMDS, HiSpi, SLVS, and Sub-LVDS Receiver Timing Specifications for Intel MAX 10 Dual Supply Devices • Updated maximum f_{HCLK} and HSIO DR (high-speed I/O performance pin) specifications for -I6, -A6, -C7, -I7 speed grades in LVDS, TMDS, HiSpi, SLVS, and Sub-LVDS Receiver Timing Specifications for Intel MAX 10 Dual Supply Devices table. • Removed Internal Configuration Time information in the Uncompressed .rbf Sizes for Intel MAX 10 Devices table. • Added Internal Configuration Time tables for uncompressed .rbf files and compressed .rbf files. • Removed Preliminary tags for all tables.
November 2015	2015.11.02	• Added description to <i>Maximum Allowed Overshoot During Transitions over a 11.4-Year Time Frame</i> topic. • Added ADC_VREF Pin Leakage Current for Intel MAX 10 Devices table. • Updated the condition for "Bus-hold high, sustaining current" parameter from "$V_{IN} < V_{IL}$ (minimum)" to "$V_{IN} < V_{IH}$ (minimum)" in Bus Hold Parameters table.
continued...		



Date	Version	Changes
		- Updated TCCS specifications in the following tables: - True PPDS and Emulated PPDS_E_3R Transmitter Timing Specifications for Intel MAX 10 Dual Supply Devices - True RSDS and Emulated RSDS_E_3R Transmitter Timing Specifications for Intel MAX 10 Dual Supply Devices - Emulated RSDS_E_1R Transmitter Timing Specifications for Intel MAX 10 Dual Supply Devices - True Mini-LVDS and Emulated Mini-LVDS_E_3R Transmitter Timing Specifications for Intel MAX 10 Dual Supply Devices - True LVDS Transmitter Timing Specifications for Intel MAX 10 Single Supply Devices - True LVDS Transmitter Timing Specifications for Intel MAX 10 Dual Supply Devices - Emulated LVDS_E_3R Transmitter Timing Specifications for Intel MAX 10 Single Supply Devices - Emulated LVDS_E_3R, SLVS, and Sub-LVDS Transmitter Timing Specifications for Intel MAX 10 Dual Supply Devices - Updated $t_{x \text{ jitter}}$ specifications in the following tables: - True PPDS and Emulated PPDS_E_3R Transmitter Timing Specifications for Intel MAX 10 Dual Supply Devices - True RSDS and Emulated RSDS_E_3R Transmitter Timing Specifications for Intel MAX 10 Dual Supply Devices - Emulated RSDS_E_1R Transmitter Timing Specifications for Intel MAX 10 Dual Supply Devices - True Mini-LVDS and Emulated Mini-LVDS_E_3R Transmitter Timing Specifications for Intel MAX 10 Dual Supply Devices - True LVDS Transmitter Timing Specifications for Intel MAX 10 Dual Supply Devices - Emulated LVDS_E_3R, SLVS, and Sub-LVDS Transmitter Timing Specifications for Intel MAX 10 Dual Supply Devices - Updated SW specifications in LVDS Receiver Timing Specifications for Intel MAX 10 Single Supply Devices table. - Added a note to $t_{x \text{ jitter}}$ for all LVDS tables. Note: TX jitter is the jitter induced from core noise and I/O switching noise. - Updated the description for t_{LOCK} for all LVDS tables: Time required for the PLL to lock, after CONF_DONE signal goes high, indicating the completion of device configuration. - Updated Memory Output Clock Jitter Specifications section. - Updated maximum external memory interfaces frequency from 300 MHz to 303 MHz. - Updated PLL output routing from global clock network to PHY clock network. - Added I/O Timing for Intel MAX 10 Devices table. - Added V_{HYS} in the Glossary table.
January 2015	2015.01.23	- Removed a note to V_{CCA} in Power Supplies Recommended Operating Conditions for Intel MAX 10 Dual Supply Devices table. This note is not valid: All V_{CCA} pins must be connected together for EQFP package. - Corrected the maximum value for $t_{\text{OUTJITTER_CCJ_IO}}$ ($F_{\text{OUT}} \geq 100 \text{ MHz}$) from 60 ps to 650 ps in PLL Specifications for Intel MAX 10 Devices table.
December 2014	2014.12.15	- Restructured Programming/Erase Specifications for Intel MAX 10 Devices table to add temperature specifications that affect the data retention duration. - Added statements in the I/O Pin Leakage Current section: Input channel leakage of ADC I/O pins due to hot socket is up to maximum of 1.8 mA. The input channel leakage occurs when the ADC IP core is enabled or disabled. This is applicable to all Intel MAX 10 devices with ADC IP core, which are 10M04, 10M08, 10M16, 10M25, 10M40, and 10M50 devices. The ADC I/O pins are in Bank 1A. - Added a statement in the I/O Standards Specifications section: You must perform timing closure analysis to determine the maximum achievable frequency for general purpose I/O standards.

continued...